

AN79L00/AN79L00M Series

3-pin Negative Output Voltage Regulator (100mA Type)

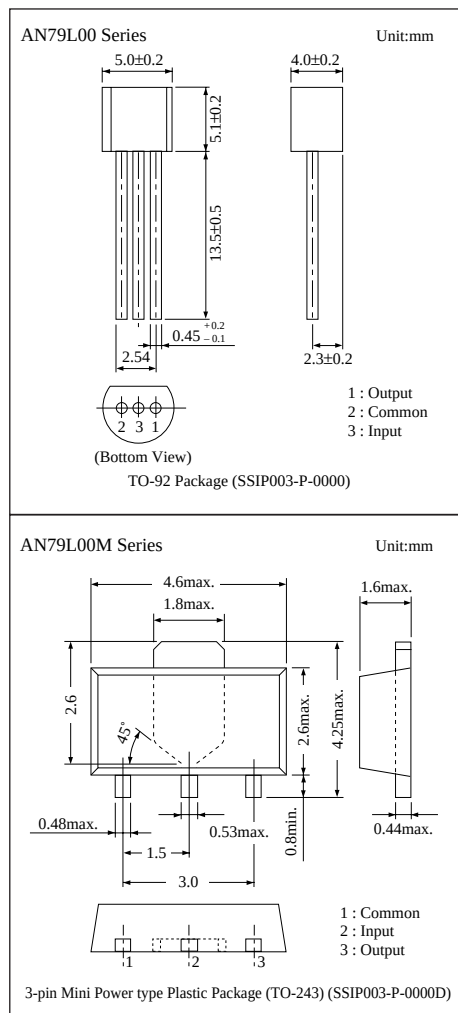
Overview

The AN79L00 series is 3-pin fixed negative output voltage regulator.

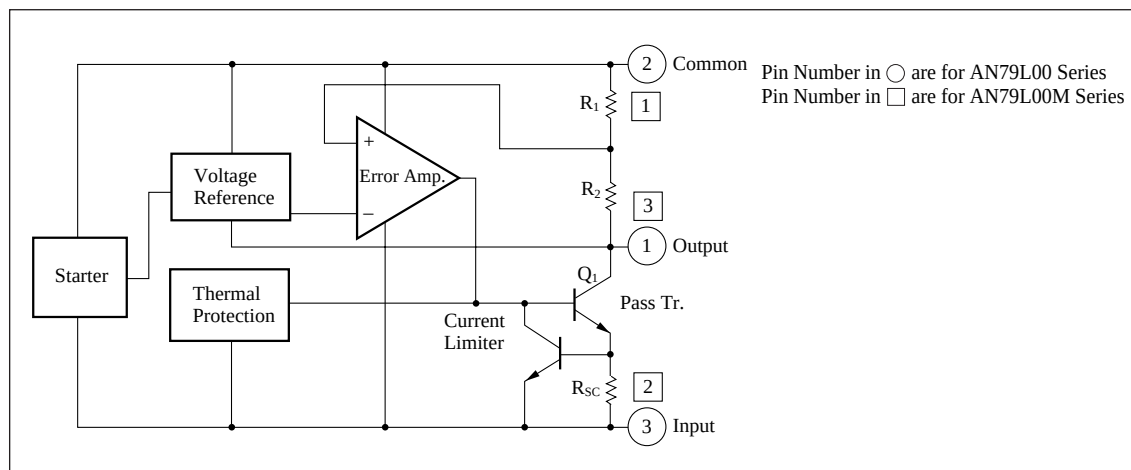
Stabilized fixed output voltage is obtained from unstable DC input voltage without using any external components. 12 types of output voltage are available; $-4V$, $-5V$, $-6V$, $-7V$, $-8V$, $-9V$, $-10V$, $-12V$, $-15V$, $-18V$, $-20V$ and $-24V$. They can be used widely in power circuits with current capacitance up to 100mA.

Features

- No external components
- Output voltage : $-4V$, $-5V$, $-6V$, $-7V$, $-8V$, $-9V$, $-10V$, $-12V$, $-15V$, $-18V$, $-20V$, $-24V$
- Short-circuit current limiting built-in
- Thermal overload protection built-in



Block Diagram



■ Absolute Maximum Ratings (Ta=25°C)

Parameter		Symbol	Rating	Unit
Input voltage		V _I	−35 * ¹	V
			−40 * ²	V
Power dissipation		P _D	650 * ³	mW
Operating ambient temperature		T _{opr}	−20 to +80	°C
Storage temperature	AN79L00 Series	T _{stg}	−55 to +150	°C
	AN79L00M Series		−55 to +125	

*1 AN79L04/M, AN79L05/M, AN79L06/M, AN79L07/M, AN79L08/M, AN79L09/M, AN79L10/M, AN79L12/M, AN79L15/M, AN79L18/M

*2 AN79L20/M, AN79L24/M

*3 Follow the derating curve. When T_j exceeds 150°C, the internal circuit cuts off the output.
Mounting onto the PCB (20 × 20 × 1.7 mm glass epoxy copper foil 1 cm² or more), for AN79L00M Series.

■ Electrical Characteristics (Ta=25°C)

• AN79L04/AN79L04M (−4V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_o	$T_j=25^\circ\text{C}$	−3.84	−4	−4.16	V
Output voltage tolerance	V_o	$V_i=-7$ to −19V, $I_o=1$ to 70mA	−3.8	—	−4.2	V
Line regulation	REG_{IN}	$V_i=-6$ to −20V, $T_j=25^\circ\text{C}$	—	—	80	mV
		$V_i=-7$ to −17V, $T_j=25^\circ\text{C}$	—	—	40	mV
Load regulation	REG_L	$I_o=1$ to 100mA, $T_j=25^\circ\text{C}$	—	10	60	mV
		$I_o=1$ to 40mA, $T_j=25^\circ\text{C}$	—	4.5	30	mV
Bias current	I_{Bias}	$T_j=25^\circ\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{bias (IN)}$	$V_i=-7$ to −19V, $T_j=25^\circ\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{bias (L)}$	$I_o=1$ to 40mA, $T_j=25^\circ\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz, $T_a=25^\circ\text{C}$	—	38	—	μV
Ripple rejection ratio	RR	$V_i=-7$ to −17V, $f=120\text{Hz}$, $T_a=25^\circ\text{C}$	55	—	—	dB
Minimum input/output voltage difference	$V_{DIF (min.)}$	$T_j=25^\circ\text{C}$	—	0.8	—	V
Output short circuit current	$I_{O (Short)}$	$V_i=-35\text{V}$, $T_j=25^\circ\text{C}$	—	200	—	mA
Output voltage temperature coefficient	$\Delta V_o/T_a$	$I_o=5\text{mA}$	—	−0.4	—	mV/°C

Note 1) The specified condition $T_j=25^\circ\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_i=-9\text{V}$, $I_o=40\text{mA}$, $C_i=2\mu\text{F}$, $C_o=1\mu\text{F}$, $T_j=0$ to 125°C (AN79L04) and $T_j=0$ to 100°C (AN79L04)

■ Electrical Characteristics (Ta=25°C)

• AN79L05/AN79L05M (–5V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_J=25^\circ\text{C}$	–4.8	–5	–5.2	V
Output voltage tolerance	V_O	$V_I=-8$ to -20V , $I_O=1$ to 70mA	–4.75	—	–5.25	V
Line regulation	REG_{IN}	$V_I=-7$ to -21V , $T_J=25^\circ\text{C}$	—	—	100	mV
		$V_I=-8$ to -18V , $T_J=25^\circ\text{C}$	—	—	50	mV
Load regulation	REG_L	$I_O=1$ to 100mA , $T_J=25^\circ\text{C}$	—	11	60	mV
		$I_O=1$ to 40mA , $T_J=25^\circ\text{C}$	—	5	30	mV
Bias current	I_{Bias}	$T_J=25^\circ\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{bias (IN)}}$	$V_I=-8$ to -20V , $T_J=25^\circ\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{bias (L)}}$	$I_O=1$ to 40mA , $T_J=25^\circ\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz , $T_a=25^\circ\text{C}$	—	40	—	μV
Ripple rejection ratio	RR	$V_I=-8$ to -18V , $f=120\text{Hz}$, $T_a=25^\circ\text{C}$	55	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$T_J=25^\circ\text{C}$	—	0.8	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I=-35\text{V}$, $T_J=25^\circ\text{C}$	—	200	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	–0.4	—	$\text{mV}/^\circ\text{C}$

Note 1) The specified condition $T_J=25^\circ\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=-9\text{V}$, $I_O=40\text{mA}$, $C_I=2\mu\text{F}$, $C_O=1\mu\text{F}$, $T_J=0$ to 125°C (AN79L04) and $T_J=0$ to 100°C (AN79L04)

• AN79L06/AN79L06M (–6V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_J=25^\circ\text{C}$	–5.76	–6	–6.24	V
Output voltage tolerance	V_O	$V_I=-79$ to -21V , $I_O=1$ to 70mA	–5.7	—	–6.3	V
Line regulation	REG_{IN}	$V_I=-8$ to -22V , $T_J=25^\circ\text{C}$	—	—	120	mV
		$V_I=-9$ to -19V , $T_J=25^\circ\text{C}$	—	—	60	mV
Load regulation	REG_L	$I_O=1$ to 100mA , $T_J=25^\circ\text{C}$	—	12	60	mV
		$I_O=1$ to 40mA , $T_J=25^\circ\text{C}$	—	5.5	30	mV
Bias current	I_{Bias}	$T_J=25^\circ\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{bias (IN)}}$	$V_I=-9$ to -21V , $T_J=25^\circ\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{bias (L)}}$	$I_O=1$ to 40mA , $T_J=25^\circ\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz , $T_a=25^\circ\text{C}$	—	44	—	μV
Ripple rejection ratio	RR	$V_I=-9$ to -19V , $f=120\text{Hz}$, $T_a=25^\circ\text{C}$	55	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$T_J=25^\circ\text{C}$	—	0.8	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I=-35\text{V}$, $T_J=25^\circ\text{C}$	—	200	—	mA
Output voltage temoerature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	–0.4	—	$\text{mV}/^\circ\text{C}$

Note 1) The specified condition $T_J=25^\circ\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=-9\text{V}$, $I_O=40\text{mA}$, $C_I=2\mu\text{F}$, $C_O=1\mu\text{F}$, $T_J=0$ to 125°C (AN79L04) and $T_J=0$ to 100°C (AN79L04)

■ Electrical Characteristics (Ta=25°C)

• AN79L07/AN79L07M (–7V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_J=25^{\circ}\text{C}$	–6.72	–7	–7.28	V
Output voltage tolerance	V_O	$V_I=-10$ to -22V , $I_O=1$ to 70mA	–6.65	—	–7.35	V
Line regulation	REG_{IN}	$V_I=-9$ to -23V , $T_J=25^{\circ}\text{C}$	—	—	140	mV
		$V_I=-10$ to -20V , $T_J=25^{\circ}\text{C}$	—	—	70	mV
Load regulation	REG_{L}	$I_O=1$ to 100mA , $T_J=25^{\circ}\text{C}$	—	13	70	mV
		$I_O=1$ to 40mA , $T_J=25^{\circ}\text{C}$	—	6	40	mV
Bias current	I_{Bias}	$T_J=25^{\circ}\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{bias (IN)}}$	$V_I=-10$ to -22V , $T_J=25^{\circ}\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{bias (L)}}$	$I_O=1$ to 40mA , $T_J=25^{\circ}\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz , $T_a=25^{\circ}\text{C}$	—	48	—	μV
Ripple rejection ratio	RR	$V_I=-10$ to -20V , $f=120\text{Hz}$, $T_a=25^{\circ}\text{C}$	54	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$T_J=25^{\circ}\text{C}$	—	0.8	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I=-35\text{V}$, $T_J=25^{\circ}\text{C}$	—	200	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	– 0.5	—	$\text{mV}/^{\circ}\text{C}$

Note 1) The specified condition $T_J=25^{\circ}\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=-9\text{V}$, $I_O=40\text{mA}$, $C_I=2\mu\text{F}$, $C_O=1\mu\text{F}$, $T_J=0$ to 125°C (AN79L04) and $T_J=0$ to 100°C (AN79L04)

• AN79L08/AN79L08M (–8V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_J=25^{\circ}\text{C}$	–7.68	–8	–8.32	V
Output voltage tolerance	V_O	$V_I=-11$ to -23V , $I_O=1$ to 70mA	–7.6	—	–8.4	V
Line regulation	REG_{IN}	$V_I=-10$ to -24V , $T_J=25^{\circ}\text{C}$	—	—	160	mV
		$V_I=-11$ to -21V , $T_J=25^{\circ}\text{C}$	—	—	80	mV
Load regulation	REG_{L}	$I_O=1$ to 100mA , $T_J=25^{\circ}\text{C}$	—	15	80	mV
		$I_O=1$ to 40mA , $T_J=25^{\circ}\text{C}$	—	7	40	mV
Bias current	I_{Bias}	$T_J=25^{\circ}\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{bias (IN)}}$	$V_I=-11$ to -23V , $T_J=25^{\circ}\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{bias (L)}}$	$I_O=1$ to 40mA , $T_J=25^{\circ}\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz , $T_a=25^{\circ}\text{C}$	—	52	—	μV
Ripple rejection ratio	RR	$V_I=-11$ to -21V , $f=120\text{Hz}$, $T_a=25^{\circ}\text{C}$	54	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$T_J=25^{\circ}\text{C}$	—	0.8	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I=-35\text{V}$, $T_J=25^{\circ}\text{C}$	—	200	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	– 0.6	—	$\text{mV}/^{\circ}\text{C}$

Note 1) The specified condition $T_J=25^{\circ}\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=-9\text{V}$, $I_O=40\text{mA}$, $C_I=2\mu\text{F}$, $C_O=1\mu\text{F}$, $T_J=0$ to 125°C (AN79L04) and $T_J=0$ to 100°C (AN79L04)

■ Electrical Characteristics (Ta=25°C)

• AN79L09/AN79L09M (–9V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_J=25^{\circ}\text{C}$	–8.64	–9	–9.36	V
Output voltage tolerance	V_O	$V_I=-12$ to -24V , $I_O=1$ to 70mA	–8.55	—	–9.45	V
Line regulation	REG_{IN}	$V_I=-11$ to -25V , $T_J=25^{\circ}\text{C}$	—	—	160	mV
		$V_I=-12$ to -22V , $T_J=25^{\circ}\text{C}$	—	—	80	mV
Load regulation	REG_{L}	$I_O=1$ to 100mA , $T_J=25^{\circ}\text{C}$	—	16	90	mV
		$I_O=1$ to 40mA , $T_J=25^{\circ}\text{C}$	—	8	50	mV
Bias current	I_{Bias}	$T_J=25^{\circ}\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{bias (IN)}}$	$V_I=-12$ to -24V , $T_J=25^{\circ}\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{bias (L)}}$	$I_O=1$ to 40mA , $T_J=25^{\circ}\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz , $T_a=25^{\circ}\text{C}$	—	58	—	μV
Ripple rejection ratio	RR	$V_I=-12$ to -22V , $f=120\text{Hz}$, $T_a=25^{\circ}\text{C}$	53	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$T_J=25^{\circ}\text{C}$	—	0.8	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I=-35\text{V}$, $T_J=25^{\circ}\text{C}$	—	200	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	– 0.6	—	$\text{mV}/^{\circ}\text{C}$

Note 1) The specified condition $T_J=25^{\circ}\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=-9\text{V}$, $I_O=40\text{mA}$, $C_I=2\mu\text{F}$ and $C_O=1\mu\text{F}$, $T_J=0$ to 125°C (AN79L04) and $T_J=0$ to 100°C (AN79L04)

• AN79L10/AN79L10M (–10V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_J=25^{\circ}\text{C}$	–9.6	–10	–10.4	V
Output voltage tolerance	V_O	$V_I=-13$ to -25V , $I_O=1$ to 70mA	–9.5	—	–10.5	V
Line regulation	REG_{IN}	$V_I=-12$ to -26V , $T_J=25^{\circ}\text{C}$	—	—	160	mV
		$V_I=-13$ to -23V , $T_J=25^{\circ}\text{C}$	—	—	80	mV
Load regulation	REG_{L}	$I_O=1$ to 100mA , $T_J=25^{\circ}\text{C}$	—	17	100	mV
		$I_O=1$ to 40mA , $T_J=25^{\circ}\text{C}$	—	9	50	mV
Bias current	I_{Bias}	$T_J=25^{\circ}\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{bias (IN)}}$	$V_I=-13$ to -25V , $T_J=25^{\circ}\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{bias (L)}}$	$I_O=1$ to 40mA , $T_J=25^{\circ}\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz , $T_a=25^{\circ}\text{C}$	—	65	—	μV
Ripple rejection	RR	$V_I=-13$ to -23V , $f=120\text{Hz}$, $T_a=25^{\circ}\text{C}$	53	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$T_J=25^{\circ}\text{C}$	—	0.8	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I=-35\text{V}$, $T_J=25^{\circ}\text{C}$	—	200	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	– 0.7	—	$\text{mV}/^{\circ}\text{C}$

Note 1) The specified condition $T_J=25^{\circ}\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=-9\text{V}$, $I_O=40\text{mA}$, $C_I=2\mu\text{F}$, $C_O=1\mu\text{F}$, $T_J=0$ to 125°C (AN79L04) and $T_J=0$ to 100°C (AN79L04)

■ Electrical Characteristics (Ta=25°C)

• AN79L12/AN79L12M (–12V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_J=25^{\circ}\text{C}$	–11.5	–12	–12.5	V
Output voltage tolerance	V_O	$V_I=-15$ to -27V , $I_O=1$ to 70mA	–11.4	—	–12.6	V
Line regulation	REG_{IN}	$V_I=-14.5$ to -30V , $T_J=25^{\circ}\text{C}$	—	—	200	mV
		$V_I=-15$ to -25V , $T_J=25^{\circ}\text{C}$	—	—	100	mV
Load regulation	REG_{L}	$I_O=1$ to 100mA , $T_J=25^{\circ}\text{C}$	—	20	100	mV
		$I_O=1$ to 40mA , $T_J=25^{\circ}\text{C}$	—	10	50	mV
Bias current	I_{Bias}	$T_J=25^{\circ}\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{bias (IN)}}$	$V_I=-15$ to -27V , $T_J=25^{\circ}\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{bias (L)}}$	$I_O=1$ to 40mA , $T_J=25^{\circ}\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz , $T_a=25^{\circ}\text{C}$	—	75	—	μV
Ripple rejection ratio	RR	$V_I=-15$ to -25V , $f=120\text{Hz}$, $T_a=25^{\circ}\text{C}$	52	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$T_J=25^{\circ}\text{C}$	—	0.8	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I=-35\text{V}$, $T_J=25^{\circ}\text{C}$	—	200	—	mA
Output voltage temperature	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	–0.8	—	$\text{mV}/^{\circ}\text{C}$

Note 1) The specified condition $T_J=25^{\circ}\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=-9\text{V}$, $I_O=40\text{mA}$, $C_I=2\mu\text{F}$, $C_O=1\mu\text{F}$, $T_J=0$ to 125°C (AN79L04) and $T_J=0$ to 100°C (AN79L04)

• AN79L15T/AN79L15M (–15V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_J=25^{\circ}\text{C}$	–14.4	–15	–15.6	V
Output voltage tolerance	V_O	$V_I=-18$ to -28V , $I_O=1$ to 70mA	–14.25	—	–15.75	V
Line regulation	REG_{IN}	$V_I=-17.5$ to -33V , $T_J=25^{\circ}\text{C}$	—	—	200	mV
		$V_I=-18$ to -28V , $T_J=25^{\circ}\text{C}$	—	—	100	mV
Load regulation	REG_{L}	$I_O=1$ to 100mA , $T_J=25^{\circ}\text{C}$	—	25	130	mV
		$I_O=1$ to 40mA , $T_J=25^{\circ}\text{C}$	—	12	60	mV
Bias current	I_{Bias}	$T_J=25^{\circ}\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{bias (IN)}}$	$V_I=-18$ to -30V , $T_J=25^{\circ}\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{bias (L)}}$	$I_O=1$ to 40mA , $T_J=25^{\circ}\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz , $T_a=25^{\circ}\text{C}$	—	90	—	μV
Ripple rejection ratio	RR	$V_I=-18$ to -28V , $f=120\text{Hz}$, $T_a=25^{\circ}\text{C}$	51	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$T_J=25^{\circ}\text{C}$	—	0.8	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I=-35\text{V}$, $T_J=25^{\circ}\text{C}$	—	200	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	–0.9	—	$\text{mV}/^{\circ}\text{C}$

Note 1) The specified condition $T_J=25^{\circ}\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=-9\text{V}$, $I_O=40\text{mA}$, $C_I=2\mu\text{F}$, $C_O=1\mu\text{F}$, $T_J=0$ to 125°C (AN79L04) and $T_J=0$ to 100°C (AN79L04)

■ Electrical Characteristics (Ta=25°C)

• AN79L18T/AN79L18M (–18V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_J=25^\circ\text{C}$	–17.3	–18	–18.7	V
Output voltage tolerance	V_O	$V_I=-21$ to -33V , $I_O=1$ to 70mA	–17.1	—	–18.9	V
Line regulation	REG_{IN}	$V_I=-21$ to -33V , $T_J=25^\circ\text{C}$	—	—	200	mV
		$V_I=-21$ to -32V , $T_J=25^\circ\text{C}$	—	—	100	mV
Load regulation	REG_L	$I_O=1$ to 100mA , $T_J=25^\circ\text{C}$	—	30	160	mV
		$I_O=1$ to 40mA , $T_J=25^\circ\text{C}$	—	15	80	mV
Bias current	I_{Bias}	$T_J=25^\circ\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{bias (IN)}}$	$V_I=-21$ to -33V , $T_J=25^\circ\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{bias (L)}}$	$I_O=1$ to 40mA , $T_J=25^\circ\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz , $T_a=25^\circ\text{C}$	—	110	—	μV
Ripple rejection ratio	RR	$V_I=-22$ to -32V , $f=120\text{Hz}$, $T_a=25^\circ\text{C}$	50	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$T_J=25^\circ\text{C}$	—	0.8	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I=-35\text{V}$, $T_J=25^\circ\text{C}$	—	200	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	–1	—	$\text{mV}/^\circ\text{C}$

Note 1) The specified condition $T_J=25^\circ\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=-9\text{V}$, $I_O=40\text{mA}$, $C_I=2\mu\text{F}$, $C_O=1\mu\text{F}$, $T_J=0$ to 125°C (AN79L04) and $T_J=0$ to 100°C (AN79L04)

• AN79L20T/AN79L20M (–20V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_J=25^\circ\text{C}$	–19.2	–20	–20.8	V
Output voltage tolerance	V_O	$V_I=-23$ to -35V , $I_O=1$ to 70mA	–19	—	–21	V
Line regulation	REG_{IN}	$V_I=-23$ to -35V , $T_J=25^\circ\text{C}$	—	—	200	mV
		$V_I=-24$ to -34V , $T_J=25^\circ\text{C}$	—	—	100	mV
Load regulation	REG_L	$I_O=1$ to 100mA , $T_J=25^\circ\text{C}$	—	35	180	mV
		$I_O=1$ to 40mA , $T_J=25^\circ\text{C}$	—	17	90	mV
Bias current	I_{Bias}	$T_J=25^\circ\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{bias (IN)}}$	$V_I=-23$ to -35V , $T_J=25^\circ\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{bias (L)}}$	$I_O=1$ to 40mA , $T_J=25^\circ\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz , $T_a=25^\circ\text{C}$	—	135	—	μV
Ripple rejection ratio	RR	$V_I=-24$ to -34V , $f=120\text{Hz}$, $T_a=25^\circ\text{C}$	49	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$T_J=25^\circ\text{C}$	—	0.8	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I=-35\text{V}$, $T_J=25^\circ\text{C}$	—	200	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	–1	—	$\text{mV}/^\circ\text{C}$

Note 1) The specified condition $T_J=25^\circ\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=-9\text{V}$, $I_O=40\text{mA}$, $C_I=2\mu\text{F}$, $C_O=1\mu\text{F}$, $T_J=0$ to 125°C (AN79L04) and $T_J=0$ to 100°C (AN79L04)

■ Electrical Characteristics (Ta=25°C)

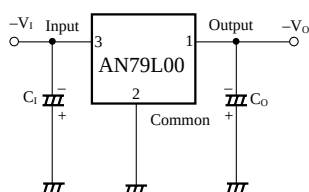
• AN79L24/AN79L24M (-24V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_j=25^\circ\text{C}$	-23	-24	-25	V
Output voltage tolerance	V_O	$V_I=-27$ to -38V , $I_O=1$ to 70mA	-22.8	—	-25.2	V
Line regulation	REG_{IN}	$V_I=-27$ to -38V , $T_j=25^\circ\text{C}$	—	—	200	mV
		$V_I=-27$ to -37V , $T_j=25^\circ\text{C}$	—	—	100	mV
Load regulation	REG_L	$I_O=1$ to 100mA , $T_j=25^\circ\text{C}$	—	40	200	mV
		$I_O=1$ to 40mA , $T_j=25^\circ\text{C}$	—	20	100	mV
Bias current	I_{Bias}	$T_j=25^\circ\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{bias (IN)}}$	$V_I=-27$ to -38V , $T_j=25^\circ\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{bias (L)}}$	$I_O=1$ to 40mA , $T_j=25^\circ\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz , $T_a=25^\circ\text{C}$	—	170	—	μV
Ripple rejection ratio	RR	$V_I=-28$ to -38V , $f=120\text{Hz}$, $T_a=25^\circ\text{C}$	49	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$T_j=25^\circ\text{C}$	—	0.8	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I=-35\text{V}$, $T_j=25^\circ\text{C}$	—	200	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	-1	—	$\text{mV}/^\circ\text{C}$

Note 1) The specified condition $T_j=25^\circ\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

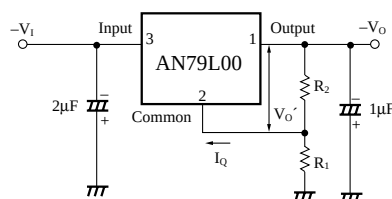
Note 2) When not specified, $V_I=-9\text{V}$, $I_O=40\text{mA}$, $C_I=2\mu\text{F}$, $C_O=1\mu\text{F}$, $T_j=0$ to 125°C (AN79L04) and $T_j=0$ to 100°C (AN79L04)

■ Basic Regulator Circuit



C_I is connected when the input line is long. $2\mu\text{F}$
 C_O improves the transient Response. $1\mu\text{F}$

■ Application Circuit



$$|V_O| = V_O' \left(1 + \frac{R_1}{R_2} \right) + I_Q R_1$$

■ Characteristic Curve

